

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10559659	KATO ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	HUY D NGUYEN	2617

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
455	456.1, 412.1, 435.1, 554.2	9/26/2008	HN
370	310, 346	9/26/2008	HN
Updated search	same above	3/29/2009	HN

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	9/26/2008	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	3/29/2009	HN
consulted with Steve D'Agosta and Tai Nguyen	3/29/2009	HN

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>